

Prediction errors

Table 1 summarizes the results achieved by all the algorithms evaluated in this work. From the results we can observe that the simple linear regression model seems to be performing the best. Thus, by considering only a small number of the past wait times we can achieve the best prediction.

Algorithm	Prediction error
DBN	0.7340
Time-based	0.5235
HMM	0.2981
Decision tree	0.2592
4-Gram Language (Reversed Markov)	0.1698
4-Gram Language (Log Linear)	0.1651
SVM	0.1636
One Order Markov	0.1629
Linear Regression	0.1582

Table 1: Prediction error of each algorithm (in hours).

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